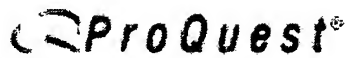


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L2	0	703/90.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 11:09
L3	628	700/90.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 11:14
L4	110	700/104.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 11:33
L5	164	700/103.ccls.	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 12:12
L6	0	"09696555"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 12:12
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L8	3	("4802091" "5630070" "5999714").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/04/11 12:13
L9	14	("4646238" "4744026" "4744027" "4885686" "4924386" "5053970" "5093794" "5101352" "5140537" "5148370" "5155679" "5172313" "5185715" "5216593").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/04/11 12:18
L10	9	"696555"	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 12:26
L11	0	ptolith	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 12:26
L12	152	prolith	US-PGPUB; USPAT; EPO; DERWENT	OR	OFF	2005/04/11 12:50

L13	152	prolith	US-PGPUB; USPAT	OR	OFF	2005/04/11 13:47
L14	2989	(expert adj system) and material and process	US-PGPUB; USPAT	OR	ON	2005/04/11 13:58
L15	2823	14 and step	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2005/04/11 13:49
L16	0	15 and (expert adj stsrem).ti.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2005/04/11 13:49
L17	59	15 and (expert adj system).ti.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2005/04/11 13:49
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L19	1704	14 and @ad<"20001212"	US-PGPUB; USPAT	OR	ON	2005/04/11 14:20
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L21	620	700/97.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/11 14:41
L22	421	21 and material	US-PGPUB; USPAT	OR	ON	2005/04/11 14:41
L23	374	22 and select\$7	US-PGPUB; USPAT	OR	ON	2005/04/11 14:42
L24	363	23 and process	US-PGPUB; USPAT	OR	ON	2005/04/11 15:00
L25	387	700/1.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/11 15:00
L26	188	25 and @ad<"20010101"	US-PGPUB; USPAT	OR	ON	2005/04/11 15:07
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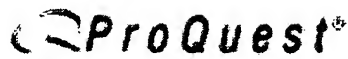
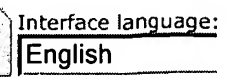
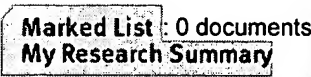
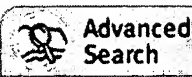
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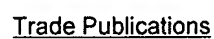
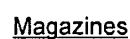
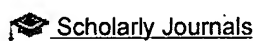
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